EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	64	transient AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:32
L2	20	transient current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
L3	6	transient current AND time AND integral AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
S1	109	defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:48
S2	63	analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:49
S3	0	transient power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50

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S4	51	power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 17:00
S5	40	fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S6	40	current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S7	37	potential AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S8	9	voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S9	9	current AND voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S10	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/22 09:34

S11	11	current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:56
S12	27	current AND voltage AND fault AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:57
S13	11	fault location AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
S14	14	(fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
S15	5	(("IC" OR integrated circuit) | (semiconductor OR semi-conductor)) AND (fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:34
S16	189433	(ishida.in. | yamaguchi.in. | hashimoto.in.)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:35
S17	36	(ishida.in. | yamaguchi.in. | hashimoto.in.) AND fault AND defect$3 AND analysis AND ("IC" | integrated circuit | semi$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:36
S18	205	(("IC" OR integrated circuit) | (semiconductor OR semi-conductor)) AND (fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41

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S19	698	(fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S20	278	current AND voltage AND fault AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S21	77	current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:42
S22	8	signal$1 AND fault AND current AND voltage AND (fault location | defect$3 signal$1) AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
S23	8	signal$1 AND fault$1 AND current AND voltage AND (fault location | defect$3 signal$1) AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
S24	26	(ishida.in. | yamaguchi.in. | hashimoto.in.) AND fault AND defect$3 AND analysis AND ("IC" | integrated circuit) AND (semi$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:48

S25	66	(stor$3 | memory | medium | media) AND current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:59
S26	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 16:40

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